



Operations Research

Publication details, including instructions for authors and subscription information:
<http://pubsonline.informs.org>

Appreciation to 1989 Referees

To cite this article:

(1990) Appreciation to 1989 Referees. *Operations Research* 38(4):736-741. <https://doi.org/10.1287/opre.38.4.736>

Full terms and conditions of use: <https://pubsonline.informs.org/Publications/Librarians-Portal/PubsOnLine-Terms-and-Conditions>

This article may be used only for the purposes of research, teaching, and/or private study. Commercial use or systematic downloading (by robots or other automatic processes) is prohibited without explicit Publisher approval, unless otherwise noted. For more information, contact permissions@informs.org.

The Publisher does not warrant or guarantee the article's accuracy, completeness, merchantability, fitness for a particular purpose, or non-infringement. Descriptions of, or references to, products or publications, or inclusion of an advertisement in this article, neither constitutes nor implies a guarantee, endorsement, or support of claims made of that product, publication, or service.

© 1990 INFORMS

Please scroll down for article—it is on subsequent pages



With 12,500 members from nearly 90 countries, INFORMS is the largest international association of operations research (O.R.) and analytics professionals and students. INFORMS provides unique networking and learning opportunities for individual professionals, and organizations of all types and sizes, to better understand and use O.R. and analytics tools and methods to transform strategic visions and achieve better outcomes. For more information on INFORMS, its publications, membership, or meetings visit <http://www.informs.org>

APPRECIATION TO 1989 REFEREES

The Editorial Board would like to thank the following individuals who have acted as referees for papers considered or published during the 1989 calendar year. Without their assistance it would be impossible for the Society to publish a journal of high professional standards.

A

E. H. L. Aarts, Phillips Research Laboratories, Eindhoven, The Netherlands
P. L. Abad, McMaster University, Hamilton, Canada
M. Abbad, University of Maryland, Baltimore County
M. S. Abdel-Hameed, Kuwait University
P. Afentakis, Syracuse University
R. Ahmadi, University of California, Los Angeles
M. Akgül, Bilkent University, Ankara, Turkey
Y. Aksoy, Tulane University
I. F. Akyildiz, Georgia Institute of Technology
S. C. Albright, Indiana University
J. M. Alden, General Motors Research Laboratories, Warren, Michigan
M. I. Al-Jazzaf, North Carolina State University
F. A. Al-Khayyal, Georgia Institute of Technology
T. Altiok, Rutgers University
M. H. Ammar, Georgia Institute of Technology
J. C. Ammons, Georgia Institute of Technology
Y. P. Aneja, University of Windsor, Ontario, Canada
F. J. Arcelus, University of New Brunswick, Fredericton, Canada
E. Arkin, Cornell University
H. Arsham, University of Baltimore
A. A. Assad, University of Maryland
D. Assaf, Hebrew University, Jerusalem, Israel
D. R. Atkins, University of British Columbia
A. H. Awni, North Carolina State University
M. Ayoub, North Carolina State University

B

U. Bagchi, University of Texas at Austin
E. Baker, University of Miami
K. R. Baker, Dartmouth College
T. E. Baker, Chesapeake Decision Science, New Providence, New Jersey
A. Balakrishnan, Massachusetts Institute of Technology
K. V. Ballman, Massachusetts Institute of Technology

R. D. Banker, Carnegie-Mellon University
J. Barcelo, Universitat Politecnica de Catalunya, Barcelona, Spain
J. F. Bard, University of Texas at Austin
J. J. Bartholdi III, Georgia Institute of Technology
Y. Bassok, Carnegie-Mellon University
J. Bather, University of Sussex, England
R. Batta, State University of New York at Buffalo
L. A. Baxter, State University of New York at Stony Brook
J. C. Bean, University of Michigan
J. E. Beasley, Imperial College of Science and Technology, London, England
E. Benavent, Universität Augsburg, F.R. Germany
O. Berman, University of Massachusetts at Boston
D. Bernstein, Massachusetts Institute of Technology
D. J. Bertsimas, Massachusetts Institute of Technology
C. Bes, 40 Avenue des Pyrénées, Muret, France
J. N. Bexfield, Institute of Defense Analysis, Alexandria, Virginia
U. N. Bhat, Southern Methodist University
D. Bienstock, Columbia University
J. R. Birge, University of Michigan
C. E. Blair, University of Illinois
J. A. Bloom, GPU Service Corporation, Parsippany, New Jersey
S. Bodily, University of Virginia
R. Boel, University of Ghent, Belgium
P. Boland, University College, Dublin, Ireland
J. H. Bookbinder, University of Waterloo
Y. A. Bozer, University of Michigan
J. Bracken, Yale University
M. L. Brandeau, Stanford University
S. S. Brown, General Electric Co., Valley Forge, Pennsylvania
S. Browne, Columbia University
R. E. Burkard, Universität Graz, Austria
R. M. Burton, Duke University
J. Busch, Johns Hopkins University
J. A. Buzacott, University of Waterloo

C

P. H. Calamai, University of Waterloo
P. Camerini, Politecnica di Milano, Italy
M. Caramanis, Boston University
J. Carlier, Université de Compiègne, France
M. W. Carter, University of Toronto
A. K. Chakravarty, University of Wisconsin, Milwaukee
S. Chand, Purdue University
G. Chandler, Management Decision Systems, Atlanta
Y.-L. Chang, University of Arizona, Tucson
X. Chao, New Jersey Institute of Technology
R. C. H. Cheng, University of Wales, Cardiff, U.K.
H.-T. Cheng, University of British Columbia
K. L. Cheung, Stanford University
S. Chiu, Stanford University
G. M. Clark, Ohio State University
R. Clemen, University of Oregon
D. A. Collier, Ohio State University
L. H. Cox, National Academy of Sciences, Washington, D.C.
D. Cristal, Georgia Institute of Technology
W. H. Cunningham, Carleton University, Ottawa, Canada

D

H. Damerdji, Stanford University
M. S. Daskin, Northwestern University
S. Dasu, University of California, Los Angeles
P. L. DeBonis, Stanford University
R. F. Deckro, University of Wyoming
R. S. Dembo, University of Toronto
L. Denenberg, Bolt, Beranak and Newman, Boston
M. Desrochers, École Polytechnique, Montréal
J. Desrosiers, University of Montreal
M. Dessouky, University of Illinois
D. DeWerra, École Polytechnique Fédérale de Lausanne, Switzerland
A. S. Dhebar, Harvard University
G. Dobson, University of Rochester
A. Dogramaci, Rutgers University, Newark
B. Doshi, AT&T Bell Laboratories, Holmdel, New Jersey
J. S. Dyer, University of Texas at Austin

E

N. Ebrahimi, Northern Illinois University
B. T. Eck, Xerox Corporation, Bedford Hills, New York

R. A. Ehrhardt, University of North Carolina, Greensboro
E. S. Elmallah, University of Alberta, Canada
E. El-Neweiki, University of Illinois at Chicago
R. A. Elsayed, Rutgers University
H. Emmons, Case Western Reserve University
D. A. Erickson, Naval Postgraduate School
S. A. Erickson, Lawrence National Laboratory, Livermore, California
A. Erramilli, Bell Communications Research, Morristown, New Jersey

F

J. E. Falk, George Washington University
Y. Fathi, North Carolina State University
A. Federgruen, Columbia University
R. M. Feldman, Texas A&M University
J. A. Filar, University of Maryland, Baltimore County
S. N. Finkelstein, Massachusetts Institute of Technology
J. R. Freeland, University of Virginia
F. G. Forst, Loyola University, Water Tower Campus
R. Fourer, Northwestern University
B. Fox, University of Colorado at Denver
K. Frauentorfer, Universität Zurich, Switzerland
J. R. Freeland, University of Virginia
T. L. Friesz, University of Pennsylvania
A. M. Frieze, Carnegie-Mellon University
E. Frostig, University of Haifa, Israel
T. Fry, University of South Carolina
S. Fujishige, University of Tsukuba, Sakura, Japan
M. Fujita, University of Pennsylvania

G

S. Gal, IBM Israel Scientific Center, Haifa, Israel
G. Gallego, Columbia University
R. S. Garfinkel, University of Connecticut
S. I. Gass, University of Maryland
H. I. Gassmann, Dalhousie University, Halifax, Canada
B. Gavish, Vanderbilt University
M. Gendreau, CRT, Montreal, Canada
Y. Gerchak, University of Waterloo
M. Ghiassi, Santa Clara University
P. Glasserman, AT&T Bell Laboratories, Holmdel, New Jersey
K. D. Glazebrook, University of Newcastle, Newcastle Upon Tyne, U.K.
A. Gleit, Citicorp Mortgage Inc., St. Louis
F. W. Glover, University of Colorado

P. W. Glynn, Stanford University
A. V. Goldberg, Stanford University
D. Goldfarb, Columbia University
D. M. Goldsman, Georgia Institute of Technology
T. Govindaraj, Georgia Institute of Technology
A. Goyal, IBM Watson Research Center, Yorktown Heights, New York
W. K. Grassmann, University of Saskatchewan, Saskatoon, Canada
R. L. Grayson, West Virginia University
L. V. Green, Columbia University
B. S. Greenberg, University of Texas at Austin
D. A. Grier, George Washington University
H. Groenevelt, University of Rochester
M. A. Grossman, Dove Associates, Boston
M. Grötschel, Universität Augsburg, F.R. Germany
S. Gupta, Columbia University
D. Gusfield, University of California, Davis
G. J. Gutierrez, University of Texas at Austin

H

S. T. Hackman, Georgia Institute of Technology
R. W. Haessler, University of Michigan
L. A. Hall, Princeton University
N. G. Hall, Ohio State University
R. W. Hall, University of California, Berkeley
S. A. Hall, Massachusetts Institute of Technology
J. Hao, GTE Laboratories, Waltham, Massachusetts
J. M. Harrison, Stanford University
P. T. Harker, University of Pennsylvania
P. J. Hass, IBM Research Center, Almaden, California
M. J. Henig, Tel-Aviv University, Israel
W. Hernandez-Lerma, Texas Technological University
W. S. Herroelen, Katholieke University Leuven, Belgium
R. Hiller, Harvard University
D. Hochbaum, University of California, Berkeley
D. S. Hopkins, Stanford University
W. J. Hopp, Northwestern University
E. C. Houck, Virginia Polytechnic University and State University
Y. H. Hsiau, University of Texas at Austin

J

P. Jackson, Cornell University
R. R. P. Jackson, University College, London, England
S. H. Jacobson, Case Western Reserve University
P. Jaillet, CERMA/ENPC, Noisy le Grand, France
M. Jaya, Syracuse University
B. Jewkes, University of Waterloo

S. G. Johansen, University of Aarhus, Denmark
D. Joneja, Columbia University
A. T. Jones, U.S. Dept. of Commerce, Gaithersburg, Maryland
P. C. Jones, Northwestern University

K

V. Kachitvichyanukul, Compaq Computer Corporation, Houston
J. Kamburowski, Wroctaw Technical University, Poland
T. Kämpke, FAW, Ulm, F.R. Germany
J. J. Kanet, Clemson University
E. P. C. Kao, University of Houston
E. H. Kaplan, Yale University
L. Kaplan, University of Tennessee
M. H. Karwan, State University of New York at Buffalo
P. Kedia, Northeastern University
S. Kekre, Carnegie-Mellon University
O. Kella, Yale University
P. Kelle, Louisiana State University
H. Kise, Kyoto Institute of Technology, Japan
J. G. Klinecicz, AT&T Bell Laboratories, Holmdel, New Jersey
D. Klingman, University of Texas at Austin
G. A. Klutke, University of Massachusetts
E. Koenigsberg, University of California, Berkeley
A. W. J. Kolen, Limburg University, Maastricht, The Netherlands
P. Kouvelis, University of Texas at Austin
W. Kubiak, University of Toronto
A. Kusiak, University of Manitoba, Winnipeg, Canada

L

B. J. Lageweg, CWI, Amsterdam, The Netherlands
T. C. Lai, Stanford University
T. Lam, University of Michigan
G. Laporte, University of Montreal
J. Lastavica, Gloucester Bank and Trust Co., Gloucester, Massachusetts
J. Lathrop, Strategic Decisions Inc., Los Altos, California
E. L. Lawler, University of California, Berkeley
S. R. Lawrence, Washington University
R. Lazimy, University of Wisconsin
L. J. LeBlanc, Vanderbilt University
P. L'Ecuyer, Université Laval, Quebec, Canada
H. L. Lee, Stanford University
C. W. Lee, Rutgers University
T. Lekane, Tractebel, Belgium

M. Lembersky, Innovis Interactive Technologies,
Tacoma, Washington
J. K. Lenstra, Eindhoven University of Technology,
The Netherlands
T. Y. Leong, National University of Singapore,
Republic of Singapore
J. Leung, Yale University
J. K. Leung, University of Texas at Dallas
L. Li, Yale University
S. C. Lin, West Virginia University
X.-G. Liu, University of Waterloo
D. P. Louchs, Cornell University
R. Love, McMaster University, Hamilton, Canada
W. S. Lovejoy, Stanford University
H. Lucas, New York University
R. Lucchetti, University of California, Davis
I. J. Lustig, Princeton University

M

M. J. Maddox, University of Michigan
F. Maffioli, Politecnica di Milano, Italy
J. W. Mamer, University of California, Los Angeles
W. G. Marchal, University of Toledo
P. Marcotte, University of Montreal
J. L. Marien, Massachusetts Institute of Technology
C. U. Martel, University of California, Davis
S. Martello, Universita degli Studi di Bologna, Italy
K. Marti, Universität des Bunderwehr, Munich, F.R.
Germany
E. Marujo, San Jose dos Campos, Brazil
H. Matsuo, University of Texas at Austin
M. Mazumdar, University of Pittsburgh
J. Mazzola, Duke University
G. P. McCormick, George Washington University
A. Mehrez, Ben-Gurion University of the Negev,
Beer Sheva, Israel
B. Melamed, AT&T Bell Laboratories, Holmdel,
New Jersey
L. Merkhofer, Applied Decision Analysis, Menlo
Park, California
B. L. Miller, University of California, Los Angeles
D. M. Miller, George Mason University
D. L. Minh, California State University, Fullerton
P. B. Mirchandani, Rensselaer Polytechnic Institute
A. Mirzaian, York University, Downsview, Canada
H. J. Miser, Farmington, Connecticut
C. M. Mitchell, Georgia Institute of Technology
J. Mittenthal, Rensselaer Polytechnic Institute
G. E. Monahan, University of Illinois
B. Montreuil, Université Laval, Quebec, Canada
R. C. Morey, University of Cincinnati
R. Motwani, Stanford University
J. A. Muckstadt, Cornell University

S. Mukherjee, Indian Institute of Technology, New
Delhi, India
S. K. Mukhopadhyay, University of Texas at Austin
J. M. Mulvey, Princeton University
F. H. Murphy, Temple University

N

S. Nahmias, Santa Clara University
T. Nakagawa, Aichi University, Toyota, Japan
S. Narasimhan, Georgia Institute of Technology
D. Nesbitt, Decision Focus Inc., Los Altos,
California
A. Nir, Tel-Aviv University, Israel
A. Nozari, Salomon Brothers, New York

O

B. Obel, Odense Universitet, Odense, Denmark
A. R. Odoni, Massachusetts Institute of Technology
P. J. O'Grady, North Carolina State University
D. L. Olsen, Texas A&M University
R. O. Onvural, North Carolina State University
J. B. Orlin, Massachusetts Institute of Technology

P

R. Padman, University of Minnesota
M. Parlar, McMaster University, Hamilton, Canada
U. Passy, Technion, Haifa, Israel
H. G. Perros, North Carolina State University
D. Perry, University of Waterloo
M. L. Pinedo, Columbia University
H. Pirkul, Ohio State University
L. K. Platzman, Georgia Institute of Technology
J. Plehn, Universität Bonn, F. R. Germany
Y. Pochet, Université Catholique de Louvain,
Belgium
T. Politof, Concordia University, Montreal, Canada
S. M. Pollock, University of Michigan
E. L. Porteus, Stanford University
M. E. Posner, Ohio State University
M. J. M. Posner, University of Toronto
C. N. Potts, University of Southampton, England
B. Pourbabai, University of Southern California
J. W. Proth, INRIA Lorraine, Metz, France
H. Psaraftis, National Technical University of
Athens
W. R. Pulleyblank, University of Waterloo
M. L. Puterman, University of British Columbia
D. Pyke, Dartmouth College

R

M. Raghavachari, Rensselaer Polytechnic Institute
J. R. Rajasekera, AT&T Bell Laboratories,
Princeton, New Jersey

V. Ramaswami, Bell Communications Research, Inc., Morristown, New Jersey
R. L. Rardin, Purdue University
H. D. Ratliff, Georgia Institute of Technology
A. Reibman, AT&T Bell Laboratories, Holmdel, New Jersey
A. V. Reklaitis, Purdue University
G. Reyman, Unilever Research Laboratorium, Vlaardingen, The Netherlands
R. L. Richter, Santa Clara University
L. W. Robinson, Cornell University
D. Ronen, University of Missouri–St. Louis
J. S. Rose, University of Richmond
M. J. Rosenblatt, Washington University
D. B. Rosenfield, Massachusetts Institute of Technology
M. Rosenwein, AT&T Bell Laboratories, Holmdel, New Jersey
R. O. Roundy, Cornell University
R. Y. Rubinstein, Technion, Haifa, Israel

S

M. H. Safizadeh, Boston College
I. Sahin, University of Wisconsin–Milwaukee
R. Salstrom, San Jose State University
M. J. Saltzman, Clemson University
D. A. Samuelson, INFOLOGIX Corporation, Reston, Virginia
J. L. Sanders, University of Wisconsin
M. W. P. Savelsbergh, CWI, Amsterdam, The Netherlands
R. Sbei, University of Virginia
R. Schassberger, Technische Universität, Braunschweig, F. R. Germany
W. T. Scherer, University of Virginia
J. F. Schmidt, Inland Steel Co., East Chicago, Illinois
V. Schmidt, Bergakademie Freiberg, Freiberg, German Democratic Republic
E. Schneider, Technische Universität Berlin, F. R. Germany
H. Schneider, Louisiana State University
I. E. Schochetman, Oakland University
R. Schrader, Universität Bonn, F. R. Germany
L. E. Schrage, University of Chicago
A. Schrijver, CWI, Amsterdam, The Netherlands
A. Schulman, GTE Laboratories, Inc. Waltham, Massachusetts
G. D. Scudder, University of Minnesota
A. Seidmann, University of Rochester
L. M. Seiford, University of Massachusetts
R. F. Serfozo, Georgia Institute of Technology
L. D. Servi, Harvard University

R. Shamir, Tel-Aviv University, Israel
S. C. Shang, University of Pittsburgh
J. G. Shanthikumar, University of California, Berkeley
A. Sharifnia, Boston University
H. D. Sherali, Virginia Polytechnic Institute and State University
C. M. Shetty, Georgia Institute of Technology
D. R. Shier, College of William and Mary
T. S. Shively, University of Texas at Austin
D. B. Shmoys, Cornell University
A. W. Shogan, University of California, Berkeley
G. Sigismondi, Georgia Institute of Technology
D. Simchi-Levi, Columbia University
B. Simons, IBM Almaden Research Center, San Jose, California
V. Singhal, General Motors Research Laboratories, Utica, Michigan
J. M. Smith, University of Massachusetts
S. A. Smith, University of Santa Clara
J. T. Sommerfeld, Georgia Institute of Technology
G. Sorger, University of Toronto
J. P. Sousa, University of Porto, Portugal
S. Spälti, École Polytechnique Fédérale de Lausanne, Switzerland
J. Spingarn, Georgia Institute of Technology
M. M. Srinivasan, University of Michigan
E. Stadlober, Technical Institute, Graz, Austria
D. Stanford, University of Western Ontario, London, Canada
J. M. Steele, Princeton University
C. Stein, Massachusetts Institute of Technology
G. Steiner, McMaster University, Hamilton, Canada
S. Stidham, University of North Carolina
M. Stoer, Universität Augsburg, F. R. Germany
L. Stougie, University of Amsterdam, The Netherlands
T. Sueyoshi, Ohio State University
U. Sumita, University of Rochester
S. Suresh, AT&T Bell Laboratories, Murray Hill, New Jersey

T

M. R. Taaffe, University of Rhode Island
Y. Takahashi, Tohoku University, Sendai, Japan
M. I. Taksar, State University of New York at Stony Brook
J. M. Tama, Northwestern University
C. S. Tang, University of California, Los Angeles
C. S. Tapiero, Hebrew University, Jerusalem, Israel
E. Tardos, Cornell University
M. Tarmicilar, Suffolk University
J. Techem, Faculté Polytechnique de Mons, Belgium

P. Thompson, University of Santa Clara
H. C. Tijms, Free University, Amsterdam, The Netherlands
D. W. Tipper, Clemson University
D. Tirupati, University of Texas at Austin
R. Tobin, GTE Laboratories, Waltham, Massachusetts
P. Toth, University of Bologna, Bologna, Italy
C. A. Tovey, Georgia Institute of Technology
M. Trick, Institute for Mathematics and Its Applications, Minneapolis
M. Tricot, École Polytechnique Fédérale de Lausanne, Switzerland
P. Tseng, Massachusetts Institute of Technology

V

R. Vachani, GTE Laboratories, Waltham, Massachusetts
P. Vakili, Boston University
L. Van Camp, Numetrix, Toronto, Canada
R. J. Vanderbei, AT&T Bell Laboratories, Murray Hill, New Jersey
J. H. Vande Vate, Georgia Institute of Technology
E. Van Doorn, University of Twente, Enschede, The Netherlands
S. van Hoesel, Erasmus University, Rotterdam, The Netherlands
S. Vanneste, Catholic University of Tilburg, Tilburg, The Netherlands
L. N. Van Wassenhove, Katholieke Universiteit Leuven, Belgium
B. Veltman, CWI, Amsterdam, The Netherlands
R. R. Vemuganti, University of Baltimore
A. Vepsalainen, University of Pennsylvania
R. G. Vickson, University of Waterloo
R. Vohra, Ohio State University
M. A. Vonderembse, University of Toledo
K. Vrieze, University of Limburg, Maastricht, The Netherlands

W

D. K. Wagner, Purdue University
E. Wagneur, École des Hautes Études Commerciales, Montréal, Canada
R. Waitman, Columbia University
J. Walrand, University of California, Berkeley

A. Warburton, Simon Fraser University, Burnaby, Canada
J. T. Warner, Clemson University
L. M. Wein, Massachusetts Institute of Technology
A. Weiss, AT&T Bell Laboratories, Murray Hill, New Jersey
G. Weiss, Georgia Institute of Technology
P. D. Welch, IBM Watson Research Center, Yorktown Heights, New York
C. C. White, University of Virginia
W. Whitt, AT&T Bell Laboratories, Murray Hill, New Jersey
P. Whittle, University of Cambridge, Cambridge, England
B.-W. Wie, University of Hawaii at Manoa
G. T. Wilfong, AT&T Bell Laboratories, Murray Hill, New Jersey
T. R. Willemain, Rensselaer Polytechnic Institute
A. C. Williams, Rutgers University
J. R. Wilson, Purdue University
W. L. Winston, Indiana University
B. Wolfe, Xerox Corporation, Tarrytown, New York
L. A. Wolsey, CORE, Louvain-la-Neuve, Belgium
R. T. Wong, Purdue University
M. H. Wright, AT&T Bell Laboratories, Murray Hill, New Jersey

X

S. Xu, Pennsylvania State University
J. Xue, Carnegie-Mellon University

Y

C. A. Yano, University of Michigan
D. D. Yao, Harvard University
U. Yechiali, Tel-Aviv University, Israel
O. S. Yu, Electric Power Research Institute, Palo Alto, California

Z

S. Zachs, State University of New York at Binghamton
M. A. Zazanis, Northwestern University
X. Zhang, Stanford University
J. Zheng, National Technical University, Singapore
Y.-S. Zheng, University of Pennsylvania
S. Zions, State University of New York at Buffalo